

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE


[Membership](#) [Publications/Services](#) [Standards](#) [Conferences](#) [Careers/Jobs](#)
**IEEE Xplore®**  
 RELEASE 1.6

 Welcome  
 United States Patent and Trademark Office


» Se

[Help](#) [FAQ](#) [Terms](#) [IEEE Peer Review](#)
**Quick Links****Welcome to IEEE Xplore®**

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

**Tables of Contents**

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

**Search**

- ☐ By Author
- ☐ Basic
- ☐ Advanced

**Member Services**

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

Your search matched **5** of **1022101** documents.A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance Descending** order.**Refine This Search:**

You may refine your search by editing the current search expression or enter a new one in the text box.

physical address&lt;and&gt;logical address

**Search**☐ Check to search within this result set**Results Key:****JNL** = Journal or Magazine   **CNF** = Conference   **STD** = Standard**1 Some solutions for FIP network interconnection***Saba, G.; Mammeri, Z.; Thomesse, J.P.;*

Factory Communication Systems, 1995. WFCS '95, Proceedings., 1995 IEEE International Workshop on , 4-6 Oct. 1995

Pages:13 - 20

[\[Abstract\]](#)   [\[PDF Full-Text \(620 KB\)\]](#)   **IEEE CNF**
**2 A space-efficient flash translation layer for CompactFlash systems***Jesung Kim; Jong Min Kim; Noh, S.H.; Sang Lyul Min; Yookun Cho;*

Consumer Electronics, IEEE Transactions on , Volume: 48 , Issue: 2 , May 20

Pages:366 - 375

[\[Abstract\]](#)   [\[PDF Full-Text \(1562 KB\)\]](#)   **IEEE JNL**
**3 Performance comparison of logical-address-to-physical-address algorithms for non-volatile memory***Jan-Ti, Y.; Sheng-Zhong Shieh; Jun-Ming Yu;*

ASIC, 2003. Proceedings. 5th International Conference on , Volume: 1 , Oct. 24, 2003

Pages:482 - 485

[\[Abstract\]](#)   [\[PDF Full-Text \(302 KB\)\]](#)   **IEEE CNF**
**4 Hypergraph coloring and reconfigured RAM testing***Franklin, M.; Saluja, K.K.;*

Computers, IEEE Transactions on , Volume: 43 , Issue: 6 , June 1994

Pages:725 - 736

[\[Abstract\]](#)   [\[PDF Full-Text \(1184 KB\)\]](#)   **IEEE JNL**

---

**5 A programmable BIST for embedded SDRAM***Zhang, M.; Tao, D.; Wei, B.;*

VLSI Technology, Systems, and Applications, 2001. Proceedings of Technical Papers. 2001 International Symposium on , 18-20 April 2001

Pages:244 - 248

[\[Abstract\]](#)[\[PDF Full-Text \(332 KB\)\]](#)**IEEE CNF**

---

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved